10/543151

## JC14 Rec'd PCT/PTO 25 JUL 2005 In the united states patent and trademark office

In re the Application of: Kenji WATANABE et al.

Serial No.: Not yet assigned

(\$371 of international application No. PCT/JP2004/000711)

Filed: July 25, 2005

MAPPING-PROJECTION-TYPE ELECTRON BEAM APPARATUS

FOR INSPECTING SAMPLE BY USING ELECTRONS EMITTED

FROM THE SAMPLE

Attorney Docket Number: 052886 Customer Number: 38834

## INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents

P. O. Box 1450

Alexandria, VA 22313-1450

Date: July 25, 2005

Sir:

In compliance with 37 C.F.R. §1.56, Applicants direct the attention of the Patent and Trademark Office to the documents listed on the attached PTO/SB/08 and cited in the enclosed international search report. Since the documents were cited in the international search report, it is believed that copies of the documents have been transmitted by the International Bureau.

In the event there are any fees due in connection with the filing of this paper, please charge Deposit Account No. 50-2866.

Respectfully submitted,

WESTERMAN, HATTORI, DAMIELS & ADRIAN, LLP

tephen G. Altrian Attorney for Applicants Registration No. 32,878

Telephone: (202) 822-1100 Facsimile: (202) 822-1111

SGA/yap

Enclosure: PTO/SB/08 and International Search Report

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Combined Form PTO/SB/08A&B

Sheet

## INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

of

	Application Number	New Application 10/543			
	Confirmation Number	1			
	Filing Date	July 25, 2005 04-18-200			
	First Named Inventor	Kenji WATANABE et al.			
	Art Unit	2881			
	Examiner Name	K. Nguyen			
_	A	052000			

Complete if Known

U.S. PATENT DOCUMENTS					
Examiner	Cite	Document Number		Publication Date	
Initials*	No.1	Number	Kind Code <sup>2</sup> (if known)	MM-DD-YYYY	Name of Patentee or Applicant of Cited Documer
		US			

FOREIGN PATENT DOCUMENTS							
Examiner	Cite No.1	Foreign Patent Document			Publication Date	Name of Patentee or	
Initials*		Country Code <sup>3</sup>	Number <sup>4</sup>	Kind Code <sup>5</sup> (if known)	MM-DD-YYYY	Applicant of Cited Document	Translation <sup>6</sup>
	TT	PCI	WU 99/46798		U9-16-1999	Hitachi Ltd.	
	2	EPO	0 949 653		10-13-1999	Hitachi Instruments Eng. et al.	
	-3	-JP	-2002-141013		-05-17-2002	Hitachi-Ltd	
	4	PCT	WO 00/72355		11/30/2000	KLA Tencor Corp. er al.	
	All I	ave be	n not rec	eived.			
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NON PATENT LITERATURE DOCUMENTS					
Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.			
		"Electron Energy Discriminator for Wafer Chip Testing", IBM Technical Disclosure Bulletin, Vol. 23.	_		
	3	No.6, November 1, 1980, pp.2288-2290.			
		W. ZHIJ et al ; "Large Current Density from Carbon Nanotube Field Emitters", Applied Physics Letters,			
	6	Vol. 75, No. 6, pp.873-875.			
		All have been not received.			

Examiner Signature	/Kiet Tuan No	juyen/	Date Considered	08/17/2008
*EXAMINER:	Initial if reference considered,	whether or not citation is in conforma	nce with MPEP 609.	Draw line through citation if not in

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conformance and not considered. Include copy of this form with next communication to applicant.